## Notice of References Cited

	Application/Control No. 10/626,521	Reexamination	Applicant(s)/Patent Under Reexamination KONNO ET AL.		
E	Examiner	Art Unit			
	M Rachuba	3723	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-2001/0008828 A1	07-2001	Uchikura et al.	451/41	
*	В	US-2001/0049912 A1	12-2001	Motonari et al.	51/307	
*	С	US-2002/0005017 A1	01-2002	Motonari et al.	51/307	
*	D	US-2002/0016275 A1	02-2002	Yano et al.	510/254	
*	Ε	US-6,383,240 B1	05-2002	Nishimoto et al.	51/307	
*	F	US-6,416,685 B1	07-2002	Zhang et al.	252/79.1	
*	G	US-6,527,818 B2	03-2003	Hattori et al.	51/308	
*	H	US-6,579,153 B2	06-2003	Uchikura et al.	451/41	
*		US-2003/0104770 A1	06-2003	Pasqualoni et al.	451/60	
*	J	US-6,749,488 B2	06-2004	Pasqualoni et al.	451/41	
	K	US-				
	L	US-				
	M	US-				

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
	V		
	w		
	X		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.